Figure S1. SEM- and TEM-images of the prepared samples: SEM: a – C3N4–Ar; TEM: b – C3N4–Ar, c – C3N4–TEOS, d – N-doped carbon.
Figure S2. Nitrogen adsorption-desorption isotherms (a) and pore size distribution (b, BJH method) for carbon nitride and carbon samples: C$_3$N$_4$–Ar (1), C$_3$N$_4$–air (2), C$_3$N$_4$–TEOS (3), N-doped carbon (4).
Figure S3. XPS spectra of C 1s region (a), N 1s region (b) and O 1s region (c) for N-doped carbon.